IN THE TITLE

Please replace the title with the following new title:

TEST CIRCUIT AND TEST METHOD FOR PROTECTING AN IC AGAINST DAMAGE FROM ACTIVATION OF TOO MANY CURRENT DRAWING CIRCUITS AT ONE TIME

IN THE SPECIFICATION

Please amend the specification as shown in marked-up form as follows:

Page 1, paragraph 1:

This is a continuation-in-part of US application No ~~90/790419~~ 09/790419(PHNL000063)

Page 3, paragraph 7:

DETAILED DESCRIPTION OF THE INVENTION

Figure 1 shows part of an integrated circuit. The integrated circuit contains power supply pins 10a-c of the integrated circuit and a power supply conductor 12 connected via respective power supply connections 18a-c. The integrated circuit also contains voltage drop measuring circuits 11a-c, control switches 13a-~~h~~K, current sources 14a-e, control circuits 16a-c and a further power supply conductor 17. The power supply conductor 12 is coupled to the further power supply conductor 17 via a number of current sources 14a-e. The control switches 13a-h are controlled by control circuits 16a-c. The voltage drop measuring circuits 11a-c are each coupled at two points to a respective one of the power supply connections 18a-c. The control circuits 16a-c are coupled in a chain, each control circuit in the chain having an output coupled to a next control circuit 16a-c in the chain.

Page 4, paragraph 7:

The first control circuit 16a signals on its output to second control circuit 16b via signals line 5a that the current sources 14a-c have been deactivated. In response, the second control circuit starts its part of the test, activating the second, third and fourth current source 14b-d and measuring the current through the second power supply connection 18b. At the end of this measurement the second control circuit 16b deactivates the current sources 14b-d and signals completion to the next control circuit 16c via its signal line 5b and so on (via signal line 5c and further signal lines. Thus the control circuits 16a-c are active one after the other, each activating a subset of the current sources 14a-e. At no time all of the current sources 14a-e are active simultaneously.